



# APEC 2026

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## **IS01.2 : Maximizing MVHV SiC Performance and Reliability with Advanced Power Device and Packaging Technologies for Mission-Critical Energy Infrastructure Applications**

Sumit Jadav

Sr. Director of Technical Marketing, Navitas Semiconductor



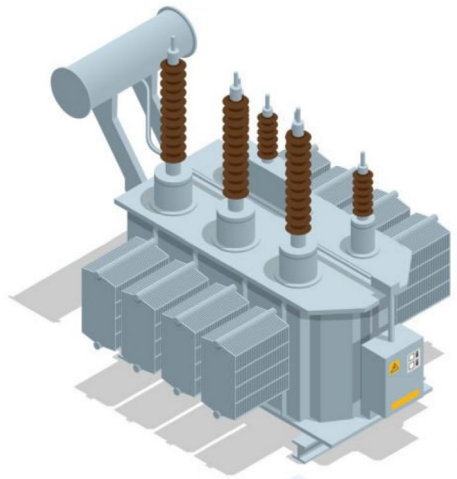
# Challenges with Existing Energy Infrastructure

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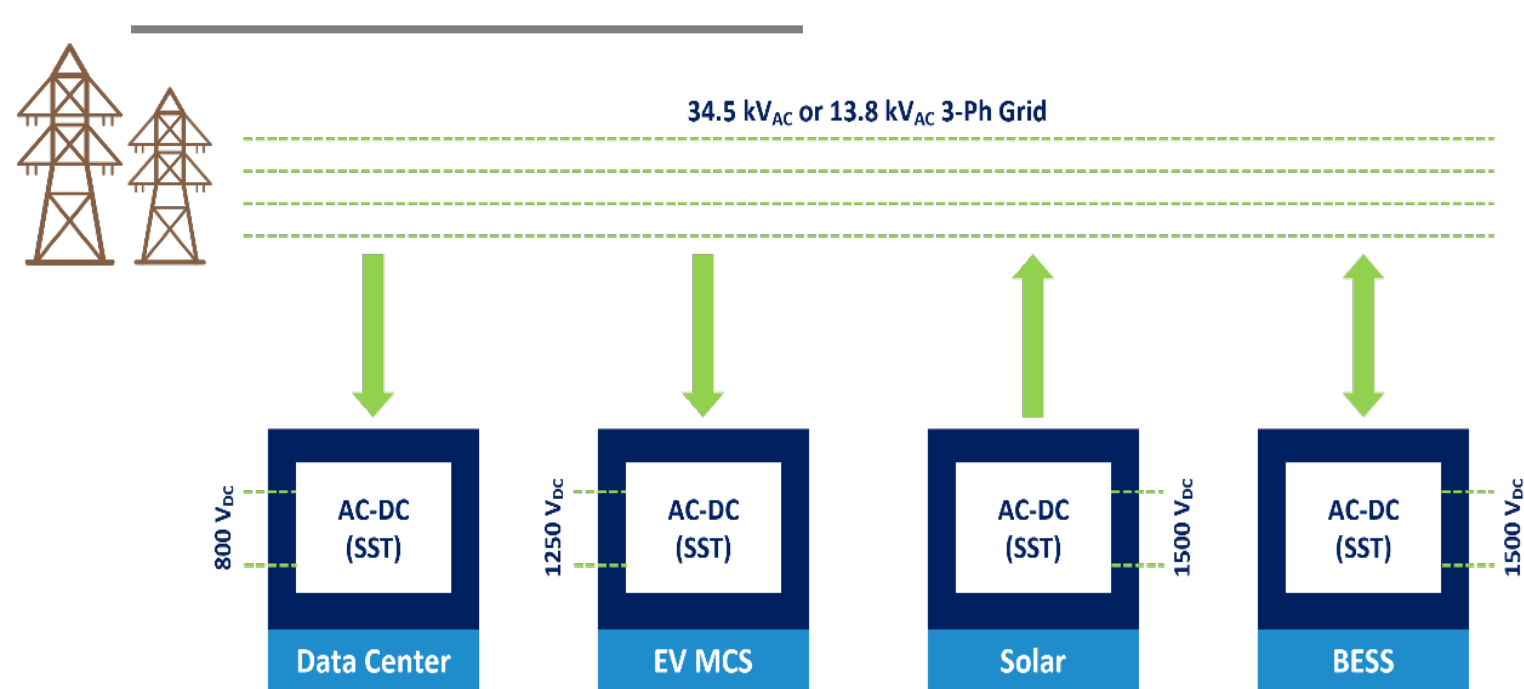
Power transformers are the backbone of power grids that provide step-up/step-down voltage conversion and are needed for galvanic isolation

Widely used line-frequency transformers have inherent limitations:

- **Low Power Density:** Operate at line-frequency (50/60 Hz), hence bulky in weight and volume causing problems for mobility and space allocation
- **Low Efficiency:** Face significant core losses and require second stage AC/DC conversion which reduces overall power transfer efficiency
- **Maintenance Nightmare:** High maintenance cost due to reliance on liquid and solid insulation systems that naturally degrade over time
- **Low Uptime:** Lack of modularity and power/voltage scalability compromises system uptime
- **Supply Shortages:** Increased lead times (over two years) and prices due to heavy reliance on copper and labor-intensive manufacturing



# Solid State Transformers : Revolutionizing Power Delivery



Line Frequency Transformer (LFT)

Medium Frequency Transformer (MFT in SST)

<b>Power Density</b>	< 1 kW / l	> 15 kW / l
<b>Frequency</b>	50/60 Hz	> 100 kHz

	MVAC Grid	DC Load / Generation
<b>Utility-Scale BESS</b>	34.5kV <sub>AC</sub> 24.5kV <sub>AC</sub> 13.8kV <sub>AC</sub>	1500V <sub>DC</sub> to 2400V <sub>DC</sub>
<b>Utility-Scale Solar</b>		1500V <sub>DC</sub> to 2000V <sub>DC</sub>
<b>Data Center Power Delivery</b>		800V <sub>DC</sub> ; Future 1500V <sub>DC</sub>
<b>EV Megawatt Charging</b>		1000V <sub>DC</sub> to 1250V <sub>DC</sub>

## Benefits of Solid State Transformer (SST):

- Single-stage AC/DC or DC/AC conversion
- Up to 1% - 2% efficiency improvement
- Over 10x reduction in size
- Modular and scalable for voltage/power
- Higher up-time (> 99%)
- Up to 50% faster construction time

# Solid State Transformer : System Overview

## AC Voltage (per Sub-System)

- ❑  $\sim 0.5 \text{ kV}_{AC}$
- ❑  $\sim 1.1 \text{ kV}_{AC}$
- ❑  $\sim 1.5 \text{ kV}_{AC}$

## DC Voltage (per Sub-System)

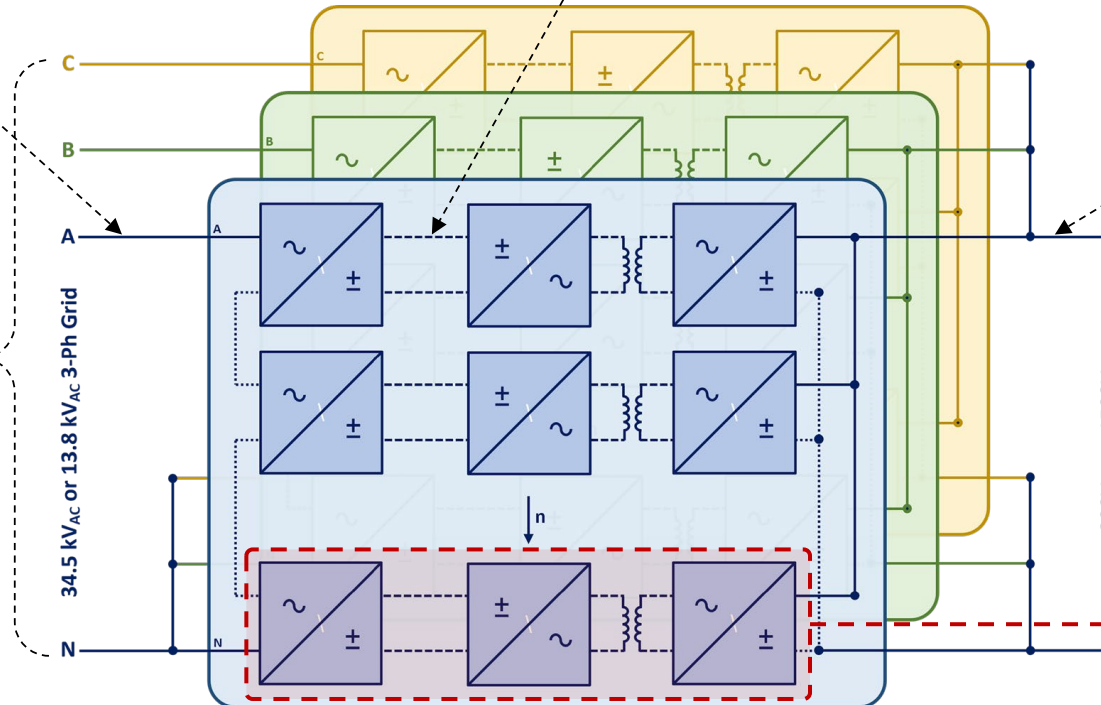
- ❑  $800 \text{ V}_{DC}$
- ❑  $1500 \text{ V}_{DC}$  to  $1800 \text{ V}_{DC}$
- ❑  $2000 \text{ V}_{DC}$  to  $2400 \text{ V}_{DC}$

## Output Voltage (per Sub-System)

- ❑  $800 \text{ V}_{DC}$  (AI Data Center)
- ❑  $1000 \text{ V}_{DC}$  to  $1250 \text{ V}_{DC}$  (EV Charging)
- ❑  $1500 \text{ V}_{DC}$  to  $2000 \text{ V}_{DC}$  (Utility-Scale Solar)
- ❑  $1500 \text{ V}_{DC}$  to  $2400 \text{ V}_{DC}$  (Utility-Scale BESS)

## MVAC Grid

- ❑  $13.8 \text{ kV}_{AC}$  (3- $\emptyset$  L-L)
- ❑  $24.5 \text{ kV}_{AC}$  (3- $\emptyset$  L-L)
- ❑  $34.5 \text{ kV}_{AC}$  (3- $\emptyset$  L-L)

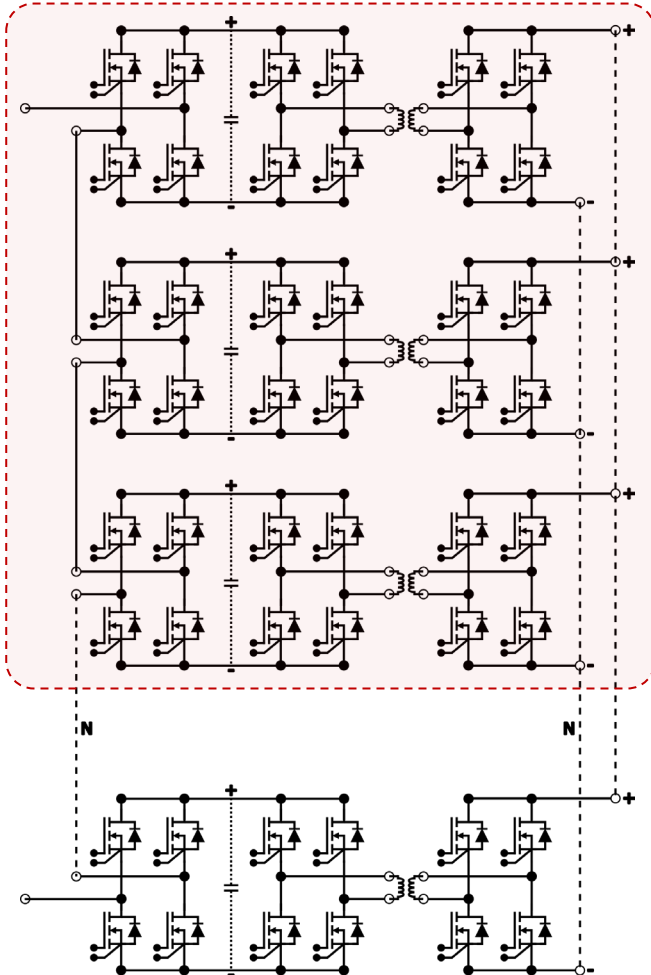


## Converter Cell (Sub-System)

- ❑ 40 kW to 400 kW per Cell
- ❑ ISOP Inter-Connection
- ❑ 1 MW to 8 MW per SST
- ❑ 1x AC-DC (ex: AFE)
- ❑ Hard-Switched (< 10 kHz)
- ❑ 1x Isolated DC-DC (ex: DAB)
- ❑ Soft-Switched (< 150 kHz)

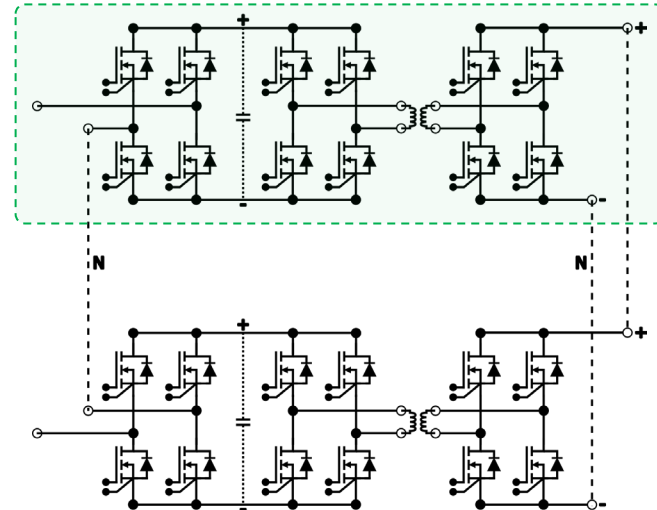
# High-Voltage SiC : Key Enabling Technology for SST

## 1200V SiC-Based Cell Architecture



Over 50% reduction in number (N) of series-connected power converter cells enabled by high-voltage SiC (> 2kV) ...

## 3300V SiC-Based Cell Architecture



## Number (N) of Cells in Series per Phase

	13.8kV <sub>AC</sub>	24.5kV <sub>AC</sub>	34.5kV <sub>AC</sub>
1.2kV SiC	16	28	40
2.3kV SiC	8	14	20
3.3kV SiC	6	10	14
6.5kV SiC	3	5	7
⋮	⋮	⋮	⋮

## Benefits of High-Voltage SiC (> 2kV) :

- > 50% reduction in series-connected cells
- Lower BOM count
- Less complex system design
- Higher system power density

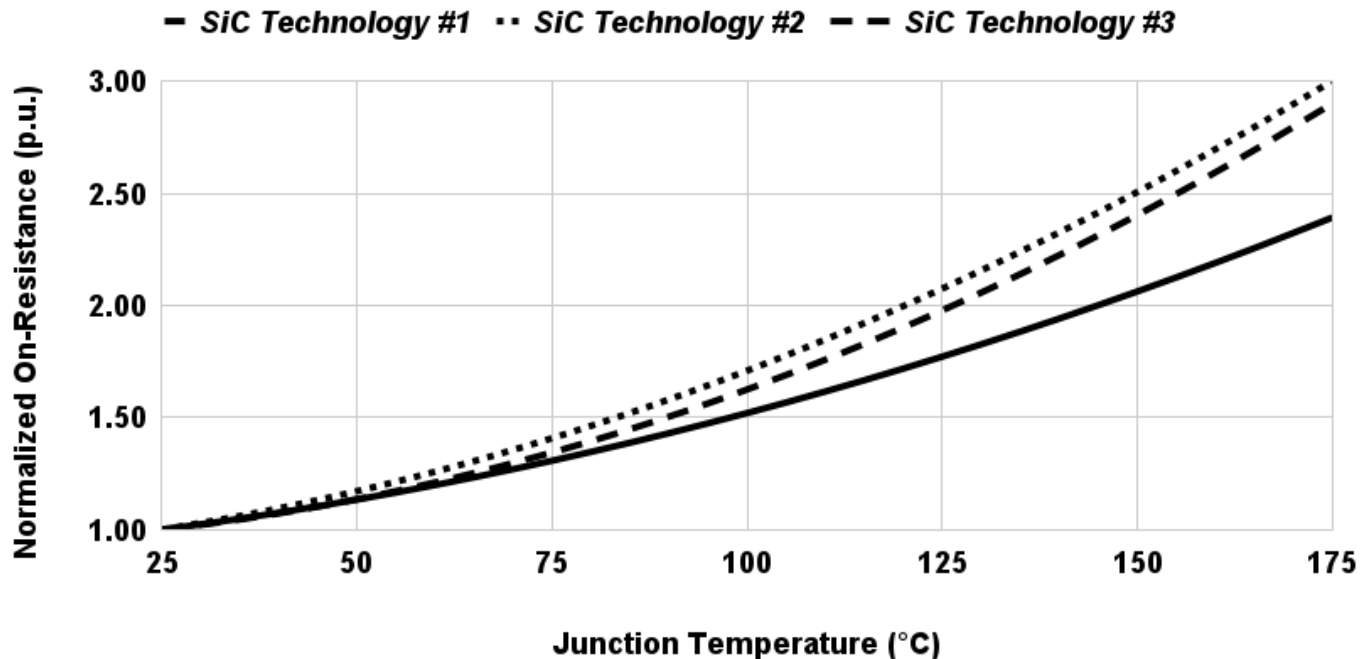
# Optimizing High-Voltage SiC for Efficiency

## Active Front End (AFE)

- ❑ Hard-switched
- ❑ < 5 kHz switching frequency typically
- ❑ Dominated by conduction loss

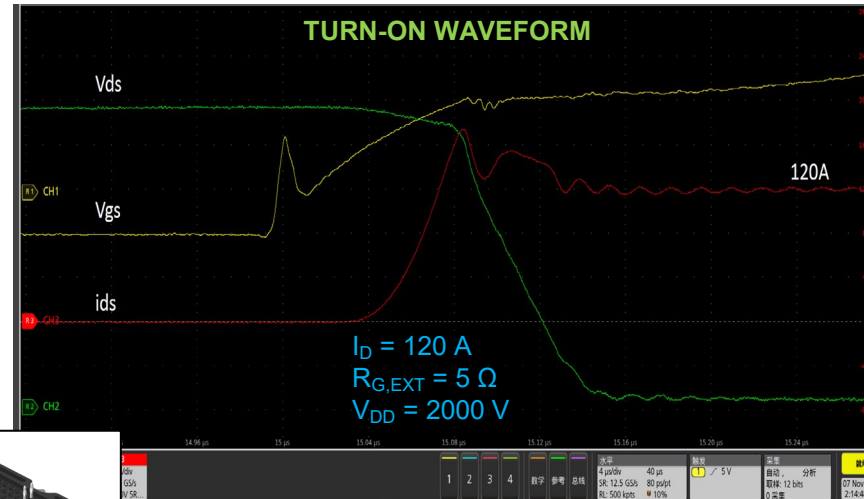
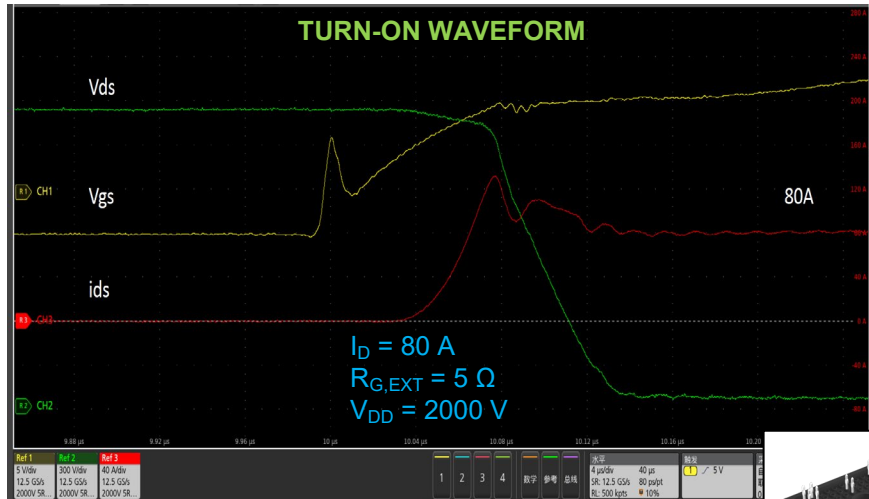
## Dual Active Bridge (DAB)

- ❑ Soft-switched
- ❑ < 150 kHz switching frequency typically
- ❑ Dominated by conduction loss



- ❑ Different high-voltage SiC MOSFET technologies exist in the market – large differences in temperature coefficient of on-state resistance ( $R_{DS,ON}$  vs.  $T_J$ )
- ❑ Selecting the right high-voltage SiC MOSFET technology with low on-state resistance across a wide temperature range helps optimize efficiency

# 3300 V 100 A SiC Power Module Switching Performance

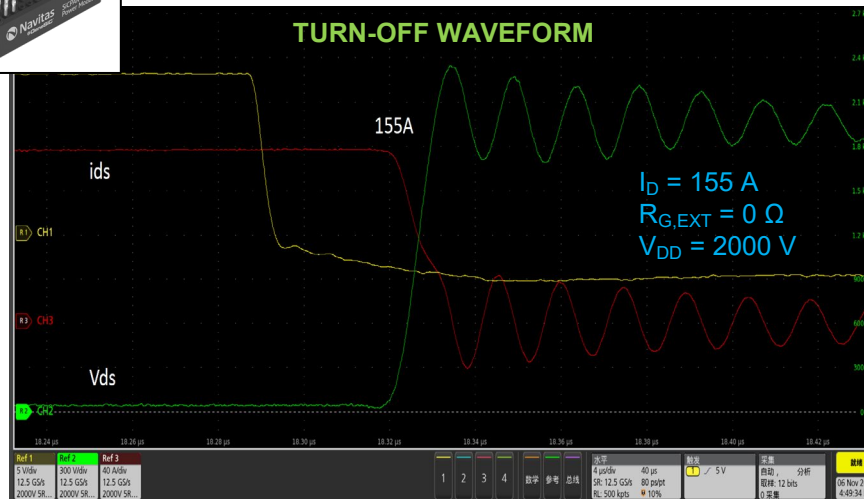
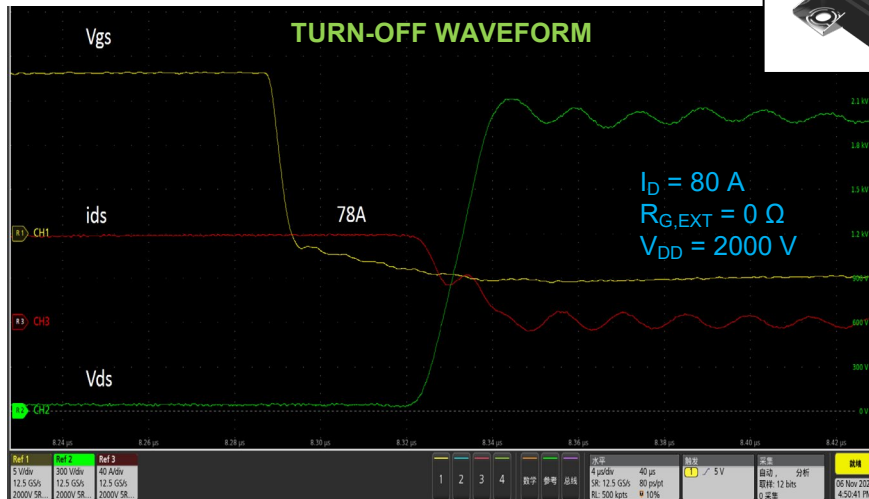


## 2000V / 80A Switching

- Turn-on  $di/dt =$  Up to 11.5 A/ns
- Turn-off  $dV/dt =$  Up to 130 V/ns

## 2000V / 120A Switching

- Turn-on  $di/dt =$  Up to 14 A/ns
- Turn-off  $dV/dt =$  Up to 160 V/ns



3300V 100A SiC Power Module Switching Waveforms (DPT)

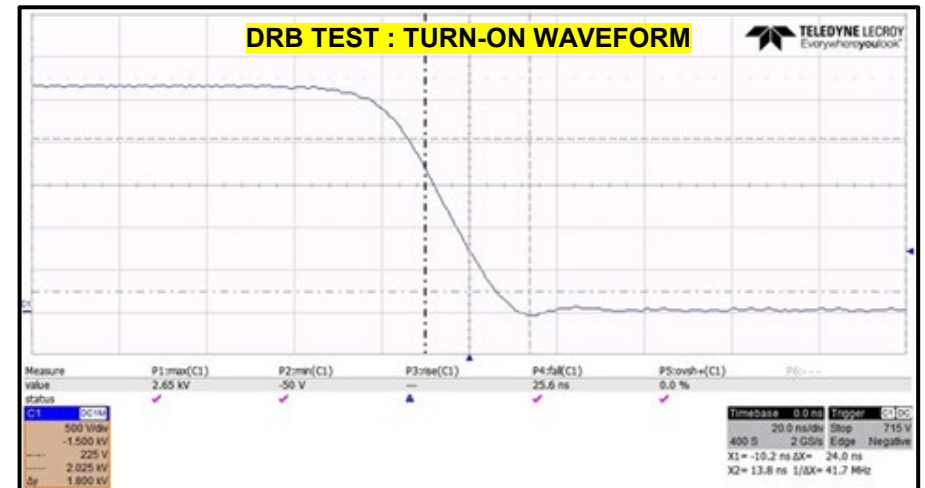
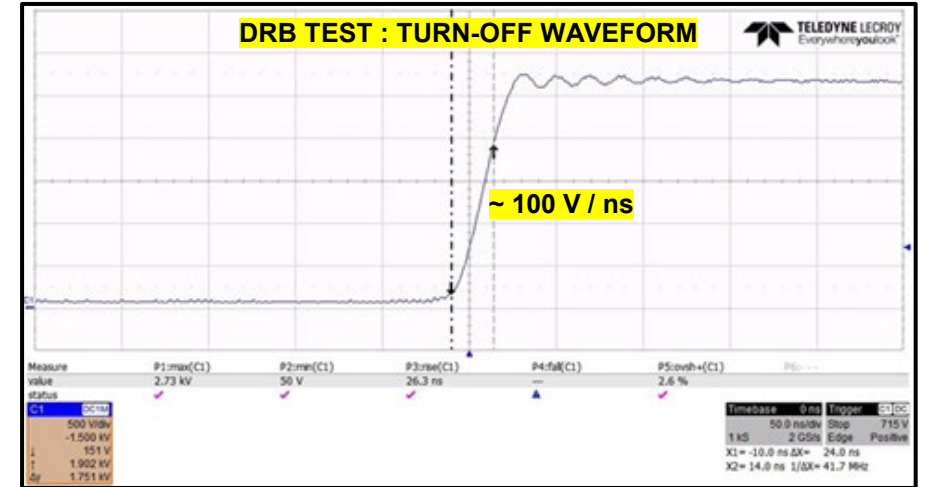
# 3300 V SiC Dynamic Reverse Bias (DRB) Reliability Test

## Reliability Validation for Repetitive High dV/dt

- ❑ Switching loss optimization at high operating frequencies (ex: 100 kHz) requires driving high-voltage SiC MOSFETs at turn-off dV/dt typically in 50 V / ns to 100 V / ns range
- ❑ dV/dt robustness validated through DRB testing

## DRB Test Conditions

- ❑  $V_{DS,static} = 2640 \text{ V}$  ( 80 % of  $V_{DS,max}$  )
- ❑  $V_{GS,static} = +20 \text{ V} / -5 \text{ V}$
- ❑  $f_{switching} = 20 \text{ kHz}$
- ❑  $dV/dt_{turn-off} = 100 \text{ V} / \text{ns}$
- ❑ Monitored parameters =  $I_{DSS}$  ,  $I_{GSS}$  ,  $V_{BV,DSS}$  ,  $V_{GS,TH}$  ,  $R_{DS,ON}$
- ❑ Test duration = 1000+ hours
- ❑ Pass criteria = shifts permissible as per AQG-324
- ❑ Accelerated testing (challenging test setup and BOM !)
  - ❑  $f_{switching} > 20 \text{ kHz}$
  - ❑  $dV/dt_{turn-off} = 100 \text{ V} / \text{ns}$  to  $200 \text{ V} / \text{ns}$



# Energy-Infrastructure Demands 20+ Years Reliability

## JEDEC

Test	Condition	Duration
HTRB	80% $V_{DS}$	1000 hours
HTGB	Max. $V_{GS-ON}$	1000 hours
HTGB-R	Max. $V_{GS-OFF}$	1000 hours
TC	-55°C to 150°C	1000 cycles
IOL ( $PC_{MIN}$ )	$\Delta T_J \geq 100^\circ C$	10,000 cycles

**+ relaxed parametric-shift criteria**

## AEC

Test	Condition	Duration
HTRB	100% $V_{DS}$	1000 hours
HTGB	Max. $V_{GS-ON}$	1000 hours
HTGB-R	Max. $V_{GS-OFF}$	1000 hours
TC	-55°C to 150°C	1000 cycles
IOL ( $PC_{MIN}$ )	$\Delta T_J \geq 100^\circ C$	10,000 cycles
H3TRB	100V $V_{DS}$	1000 hours

**+ stringent parametric-shift criteria**

## AEC-PLUS

Test	Condition	Duration
HTRB	100% $V_{DS}$	2000 hours
HTGB	Max. $V_{GS-ON}$	2000 hours
HTGB-R	Max. $V_{GS-OFF}$	2000 hours
TC	-55°C to 150°C	3000 cycles
IOL ( $PC_{MIN}$ )	$\Delta T_J \geq 100^\circ C$	30,000 cycles
HV-H3TRB	80% $V_{DS}$	1000 hours
DRB	80%/100% $V_{DS}$	1000 hours
DGS	Max. $V_{GS}$	1000 hours

**+ stringent parametric-shift criteria**

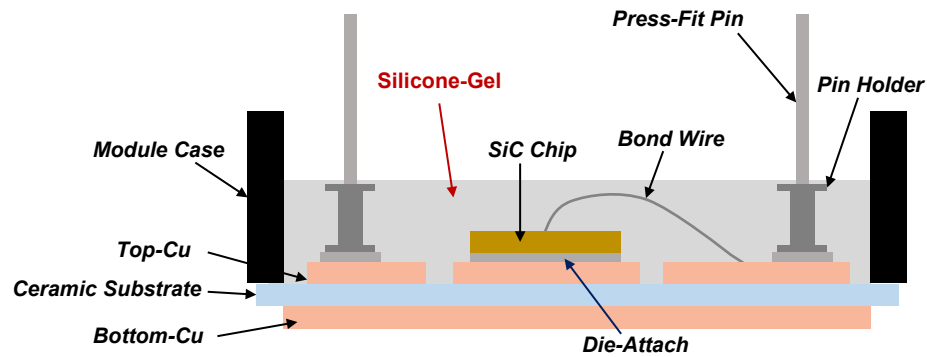
# Stringent Reliability Testing of High-Voltage SiC

Comprehensive reliability testing at SiC die level and SiC power module level ...

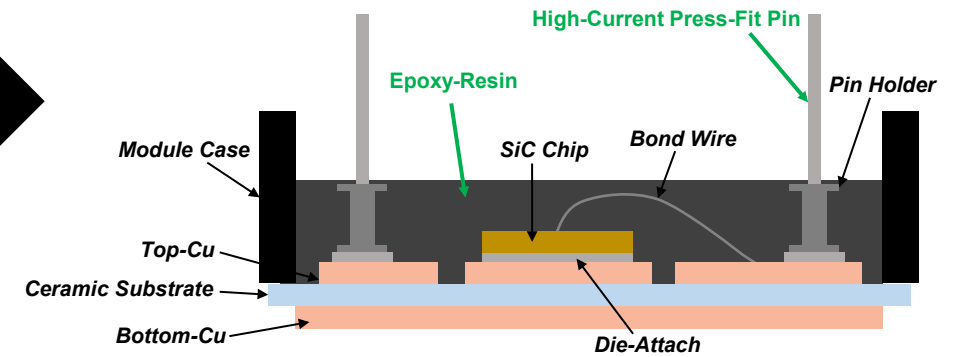
Switching Reliability Tests	Test Conditions	'AEC-Plus' Grade
Dynamic Reverse Bias (DRB)	$V_{DS,st} = 80\%$ , $V_{DS,tr} = 90\% - 100\%$ , $>20\text{kHz}$ , $>100\text{V/ns}$	1000 hr
Dynamic Gate Stress (DGS)	$V_{GS,st} = +22.5/-10\text{V}$ , $>500\text{kHz}$ , $>1\text{V/ns}$	1000 hr
Dynamic H3TRB (D-H3TRB)	$V_{DS,st} = 80\%$ , $V_{DS,tr} = 90\% - 100\%$ , $>25\text{kHz}$ , $>100\text{V/ns}$	1000 hr

Static Reliability Tests	Test Conditions	'AEC-Plus' Grade
HTGB and HTGB-R	$V_{GS,st} = +22.5\text{V} \ \& \ -10\text{V}$ , $175^\circ\text{C}$ , $V_{DS} = 0\text{V}$	2000 hr
LTGB and LTGB-R	$V_{GS,st} = +22.5\text{V} \ \& \ -10\text{V}$ , $-55^\circ\text{C}$ , $V_{DS} = 0\text{V}$	1000 hr
HTRB	$V_{DS,st} = 100\%$ , $175^\circ\text{C}$ , $V_{GS} = 0\text{V}$	2000 hr
LTRB	$V_{DS,st} = 100\%$ , $-55^\circ\text{C}$ , $V_{GS} = 0\text{V}$	1000 hr
HV-H3TRB	$V_{DS,st} = 80\%$ , $T_a = 85^\circ\text{C}$ , $\text{RH } 85\%$	1000 hr

# Improving Package Technology for Longer Lifetime

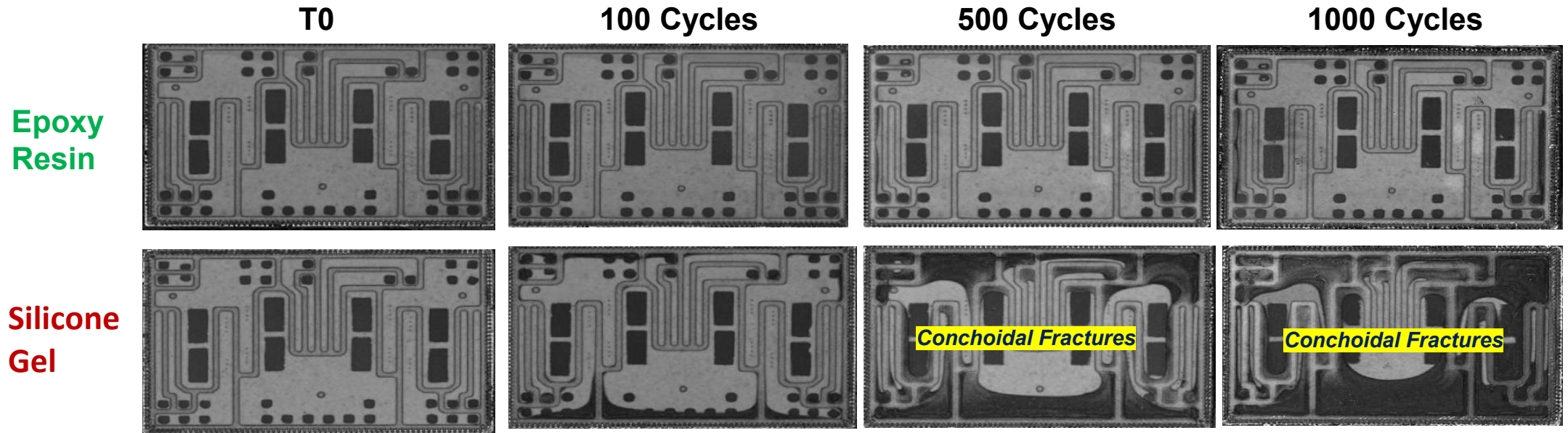


**Silicone-Gel to Epoxy**



Reliability Improvement Area	Epoxy-Resin Potting Technology	Silicone-Gel Fill Technology
Thermal Shock Test (-40°C to 125°C)	>3000 cycles	<250 cycles
Temperature Cycling (-55°C to 150°C)	>3000 cycles	<250 cycles
Power Cycling (PC <sub>sec</sub> )	+65% lifetime improvement	-
Temperature Humidity Bias (THB / HV-H3TRB)	Improved	-

# Module Technology Lifetime Validation : Thermal Shock

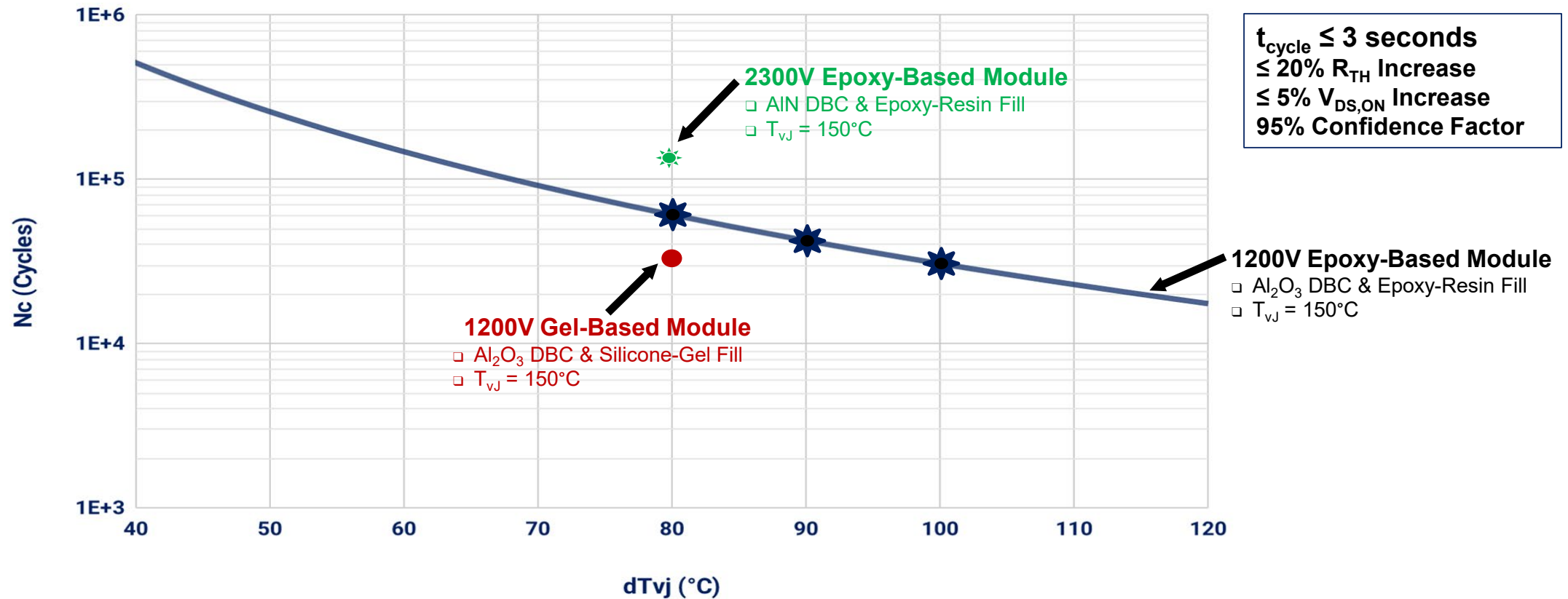


## Results\* after 1000 cycles of Thermal Shock Testing (-40°C to 125°C)

- ✓ <15% thermal resistance increase for epoxy-resin vs. 33%-80%  $R_{th}$  increase for silicone-gel
- ✓ All epoxy-resin potted modules passed isolation tests ; all silicone-gel modules failed isolation test

\* actual test data comparison based on 1200V SiC power modules with  $Al_2O_3$  DBC assembled with different potting technology methods

# Module Technology Lifetime Validation : Power Cycling



- ✓ >500k Power cycles at  $dT_j = 40^{\circ}\text{C}$  for  $\text{Al}_2\text{O}_3$  DBC based epoxy-resin potted module
  - Epoxy-resin potting technology enabled over 65% longer lifetime compared to silicone-gel
- ✓ Additional 60% lifetime improvement by changing BOM from  $\text{Al}_2\text{O}_3$  DBC to AlN AMB



# Navitas High-Voltage SiC Module Portfolio for SST



SiCPAK™ G+ (56.7mm x 65mm)

Voltage	Package	Configuration	$R_{DS,ON}$ per Switch	Part Number	Status
3300V	SiCPAK™ G+	Full-Bridge	22.5 mΩ	G4H22MT33GB4	Sampling Now
2300V		Half-Bridge	5.8 mΩ	G4H06MT23GB2	Sampling Now
		Full-Bridge	11.5 mΩ	G4H11MT23GB4	Sampling Now
		Full-Bridge	8 mΩ	G4H08MT23GB4	Sampling Now
1200V	SiCPAK™ G	Half-Bridge	4.6 mΩ	G3F05MT12GB2	In Production
1200V	SiCPAK™ G	Full-Bridge	9.3 mΩ	G3F09MT12GB4	In Production

+ more modules in development ...



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Authors' Names and Affiliations  
(Optional: Contact Information)